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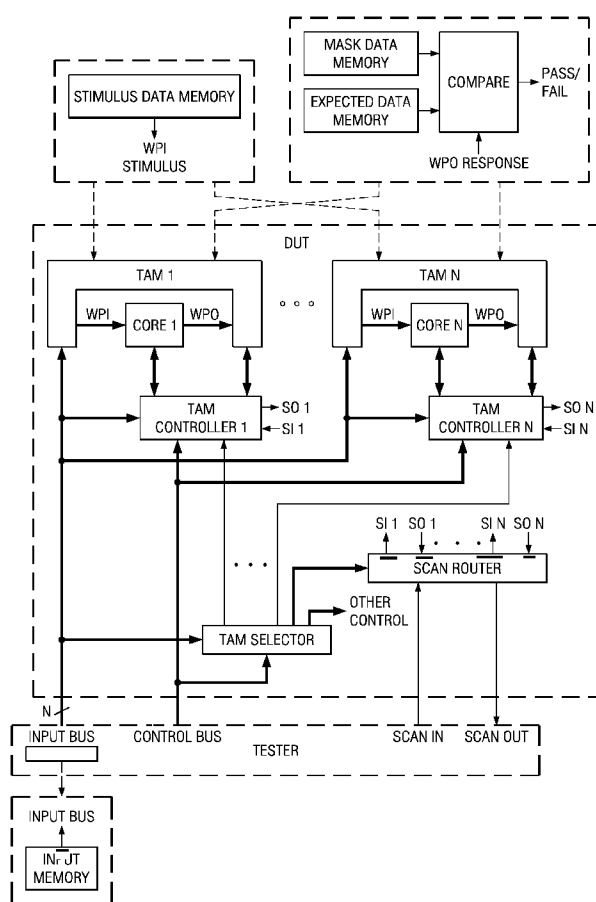
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[Continued on next page]

(54) **Title:** DOUBLE DATA RATE TEST INTERFACE AND ARCHITECTURE



(57) **Abstract:** A device test architecture (702) and a reduced device test interface are provided to enable efficient testing of embedded cores (708) and other circuits within devices. The reduced device test interface is achieved using a double data rate (DDR) signaling technique between the tester (712) and the device. The DDR test interface allows the tester to interface to test circuits within the device, such as IEEE 1500 and/or IEEE 1149.1 test circuits, to provide high test data bandwidth to the test circuits using a minimum of test interface signals. The test architecture includes compare circuits that allow for comparison of test response data to be performed within the device. The test architecture further includes a memory for storing the results of the test response comparisons. The test architecture includes a programmable test controller (706) to allow for various test control operations by simply inputting an instruction to the programmable test controller from the external tester. Additional features and embodiments of the device test architecture and reduced test interface are also disclosed.



Declarations under Rule 4.17:

- as to applicant's entitlement to apply for and be granted a patent (Rule 4.17(H))
- as to the applicant's entitlement to claim the priority of the earlier application (Rule 4.17(Hi))
- before the expiration of the time limit for amending the claims and to be republished in the event of receipt of amendments

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INTERNATIONAL SEARCH REPORT

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A. CLASSIFICATION OF SUBJECT MATTER

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USPC: 714/726,727

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

U.S. : 714/726,727

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched
US PG PUB, JPO, EPO, Derwent, IBM TDBElectronic data base consulted during the international search (name of data base and, where practicable, search terms used)
Google search, IEEE

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	US 6,938,225 B2 (Kndu Sandip) 30-Aug-05 Figure 3 Columns 2-3	1-4
X	Double edge triggered devices: Speed and power constraints Hossain et al., A. Circuits and Systems, 1993., ISCAS '93, 1993 IEEE International Symposium on May 1993, Page(s): 1491 -1494, Volume 3	1-4



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